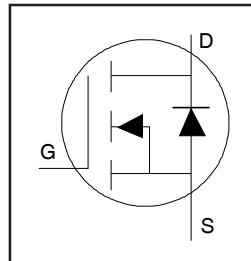


Applications

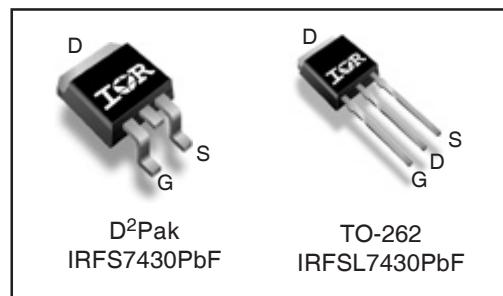
- Brushed motor drive applications
- BLDC motor drive applications
- Battery powered circuits
- Half-bridge and full-bridge topologies
- Synchronous rectifier applications
- Resonant mode power supplies
- OR-ing and redundant power switches
- DC/DC and AC/DC converters
- DC/AC inverters

Benefits

- Improved gate, avalanche and dynamic dV/dt ruggedness
- Fully characterized capacitance and avalanche SOA
- Enhanced body diode dV/dt and di/dt capability
- Lead-free



V_{DSS}	40V
R_{DS(on)} typ.	0.97mΩ
max.	1.2mΩ
I_D (Silicon Limited)	426A①
I_D (Package Limited)	195A



G	D	S
Gate	Drain	Source

Base Part Number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
IRFSL7430PbF	TO-262	Tube	50	IRFSL7430PbF
IRFS7430PbF	D2-Pak	Tube	50	IRFS7430PbF
		Tape and Reel Left	800	IRFS7430TRLPbF

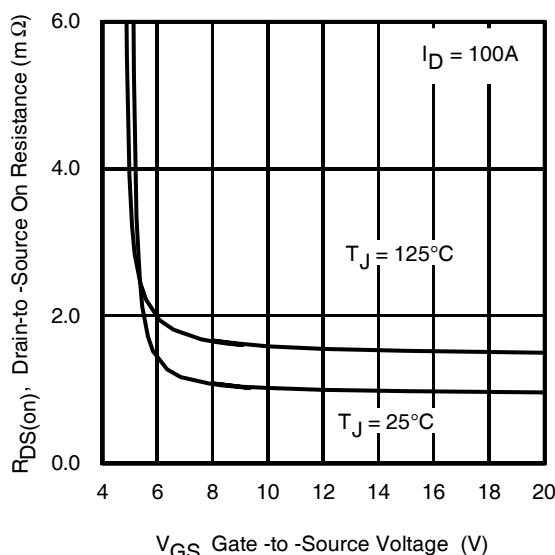


Fig 1. Typical On-Resistance vs. Gate Voltage

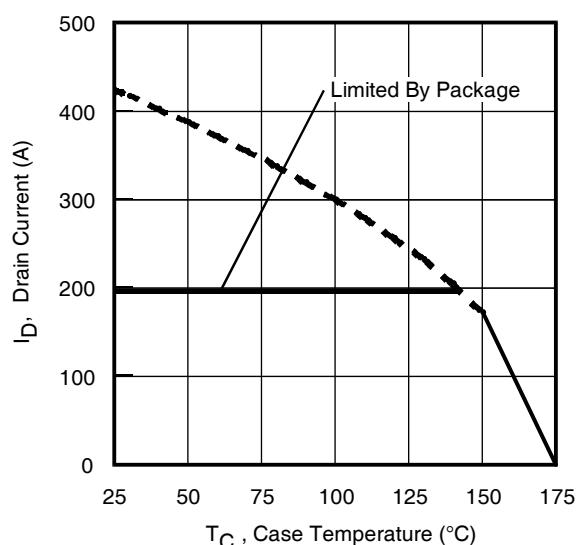


Fig 2. Maximum Drain Current vs. Case Temperature

Absolute Maximum Ratings

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	426①	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	301①	
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Wire Bond Limited)	195	
I_{DM}	Pulsed Drain Current ②	1524	
$P_D @ T_C = 25^\circ C$	Maximum Power Dissipation	375	W
	Linear Derating Factor	2.5	W/ $^\circ C$
V_{GS}	Gate-to-Source Voltage	± 20	V
T_J	Operating Junction and	-55 to + 175	$^\circ C$
T_{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Avalanche Characteristics

E_{AS} (Thermally limited)	Single Pulse Avalanche Energy ③	760	mJ
E_{AS} (Thermally limited)	Single Pulse Avalanche Energy ④	1452	
I_{AR}	Avalanche Current ②	See Fig. 15, 16, 22a, 22b	A
E_{AR}	Repetitive Avalanche Energy ②		

Thermal Resistance

Symbol	Parameter	Typ.	Max.	Units
R_{JC}	Junction-to-Case ⑤	—	0.40	$^\circ C/W$
R_{JA}	Junction-to-Ambient (PCB Mount, steady-state) ⑥	—	40	

Static @ $T_J = 25^\circ C$ (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.014	—	V/ $^\circ C$	Reference to $25^\circ C, I_D = 1.0mA$
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	0.97	1.2	$m\Omega$	$V_{GS} = 10V, I_D = 100A$ ⑦
		—	1.2	—		$V_{GS} = 6.0V, I_D = 50A$ ⑧
$V_{GS(th)}$	Gate Threshold Voltage	2.2	—	3.9	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
	Drain-to-Source Leakage Current	—	—	1.0	μA	$V_{DS} = 40V, V_{GS} = 0V$
I_{GS}	—	—	150	—		$V_{DS} = 40V, V_{GS} = 0V, T_J = 125^\circ C$
	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 20V$
I_{GSS}	Gate-to-Source Reverse Leakage	—	—	-100	nA	$V_{GS} = -20V$
	Internal Gate Resistance	—	2.1	—	Ω	

Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 195A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements. (Refer to AN-1140)
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ Limited by T_{Jmax} , starting $T_J = 25^\circ C$, $L = 0.15mH$
 $R_G = 50\Omega$, $I_{AS} = 100A$, $V_{GS} = 10V$.
- ④ $I_{SD} \leq 100A$, $di/dt \leq 990A/\mu s$, $V_{DD} \leq V_{(BR)DSS}$, $T_J \leq 175^\circ C$.
- ⑤ Pulse width $\leq 400\mu s$; duty cycle $\leq 2\%$.
- ⑥ C_{oss} eff. (TR) is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑦ C_{oss} eff. (ER) is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑧ R_0 is measured at T_J approximately $90^\circ C$.
- ⑨ Limited by T_{Jmax} starting $T_J = 25^\circ C$, $L = 1mH$, $R_G = 50\Omega$, $I_{AS} = 54A$, $V_{GS} = 10V$.
- ⑩ When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994. <http://www.irf.com/technical-info/appnotes/an-994.pdf>

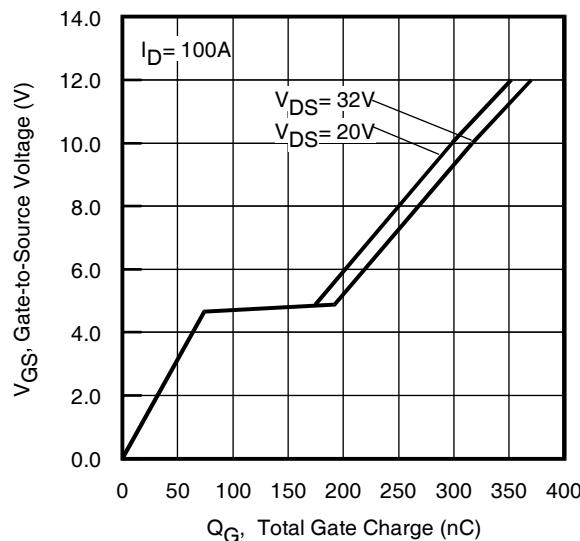
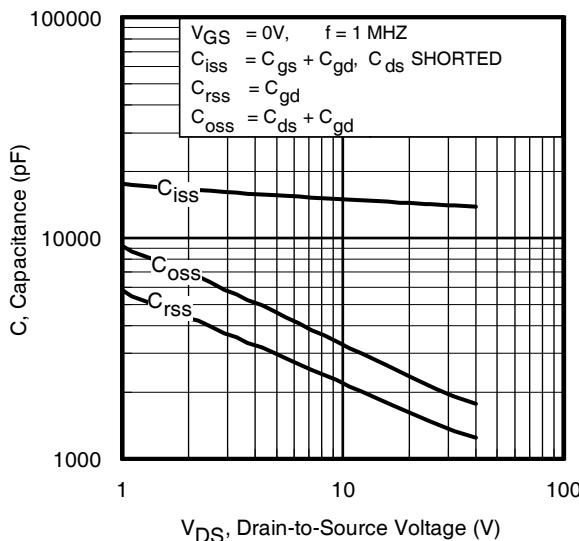
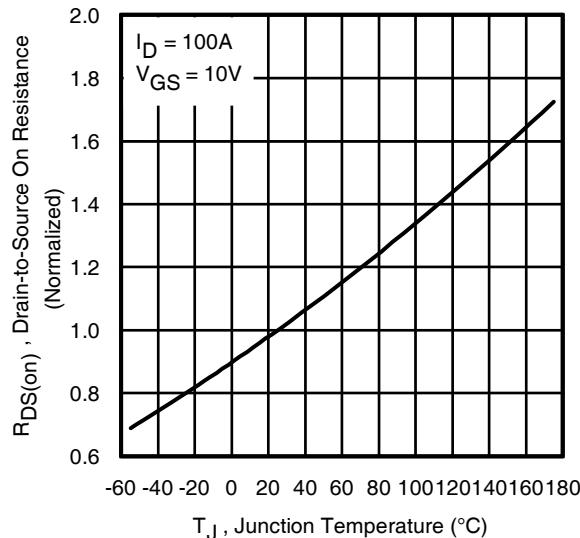
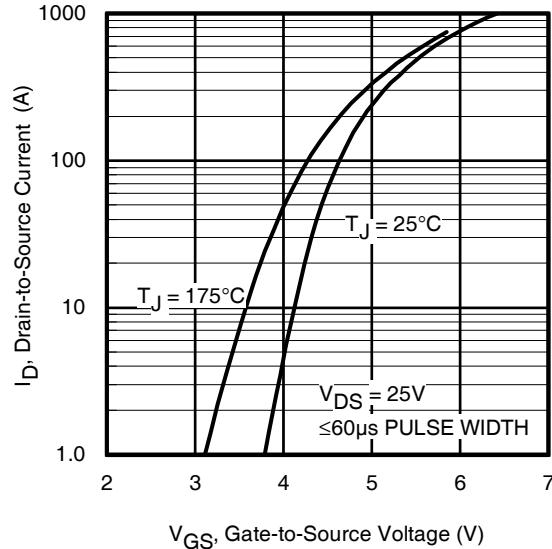
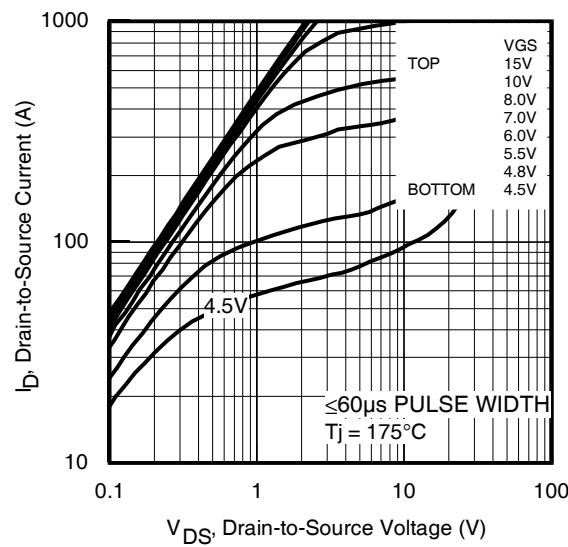
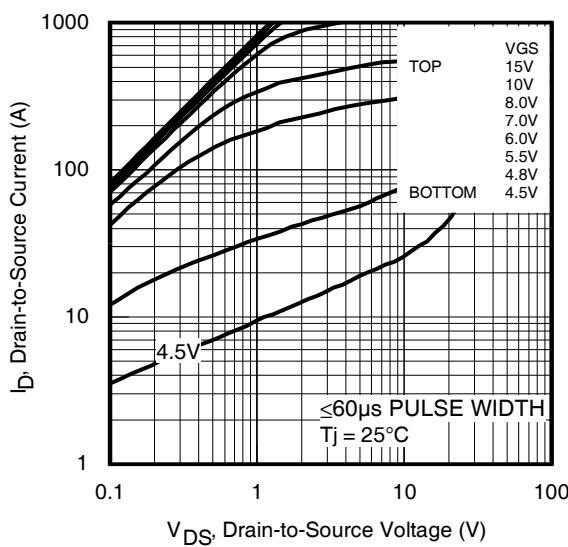
Dynamic @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

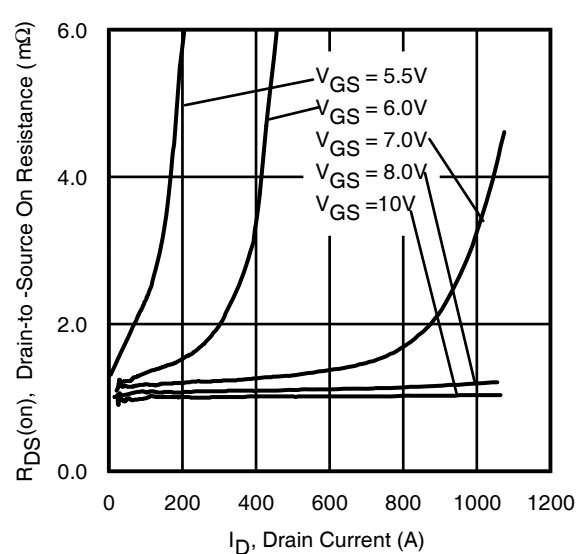
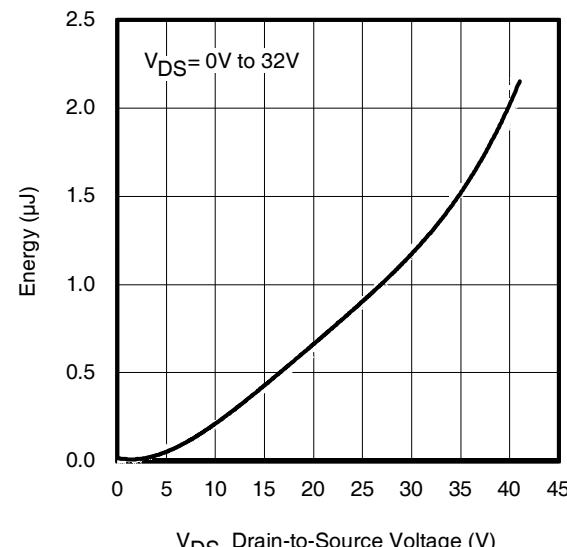
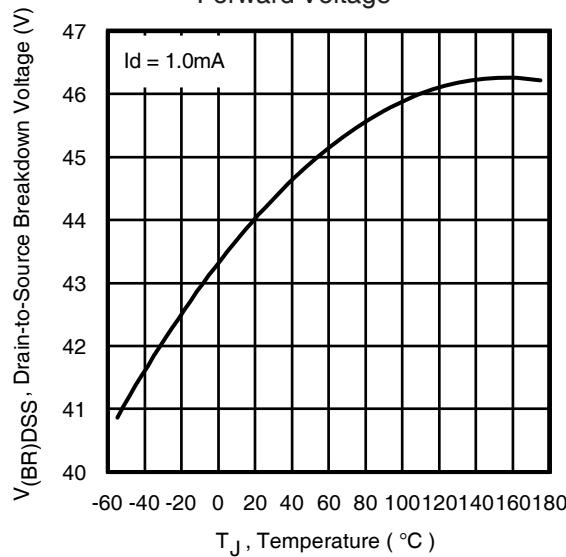
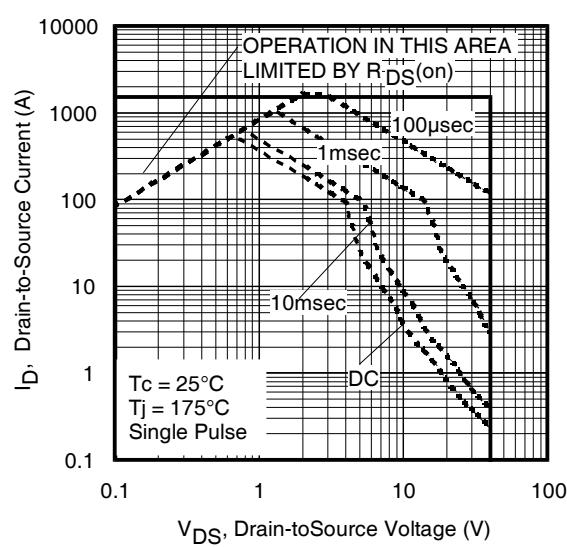
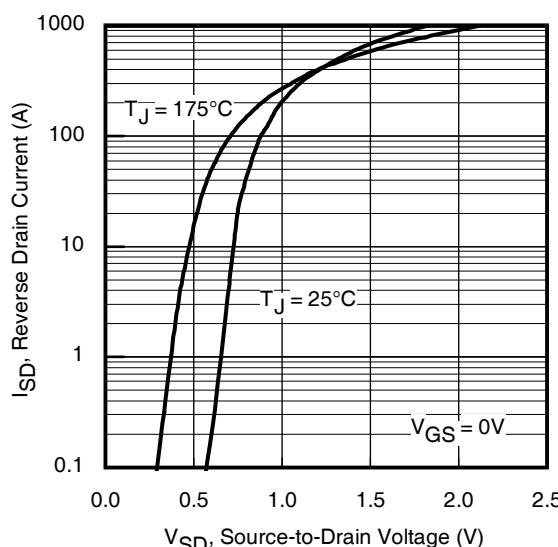
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
g_{fs}	Forward Transconductance	150	—	—	S	$V_{DS} = 10\text{V}, I_D = 100\text{A}$ $I_D = 100\text{A}$ $V_{DS} = 20\text{V}$ $V_{GS} = 10\text{V}$ ⑤ $I_D = 100\text{A}, V_{DS} = 0\text{V}, V_{GS} = 10\text{V}$
Q_g	Total Gate Charge	—	300	460	nC	
Q_{gs}	Gate-to-Source Charge	—	77	—	nC	
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	98	—	nC	
Q_{sync}	Total Gate Charge Sync. ($Q_g - Q_{gd}$)	—	202	—	nC	$I_D = 100\text{A}, V_{DS} = 0\text{V}, V_{GS} = 10\text{V}$ $V_{DD} = 20\text{V}$ $I_D = 30\text{A}$ $R_G = 2.7\Omega$ $V_{GS} = 10\text{V}$ ⑤
$t_{d(on)}$	Turn-On Delay Time	—	32	—	ns	
t_r	Rise Time	—	105	—	ns	
$t_{d(off)}$	Turn-Off Delay Time	—	160	—	ns	
t_f	Fall Time	—	100	—	ns	$V_{GS} = 0\text{V}$ $V_{DS} = 25\text{V}$ $f = 1.0 \text{ MHz}$ $V_{GS} = 0\text{V}, V_{DS} = 0\text{V to } 32\text{V}$ ⑦
C_{iss}	Input Capacitance	—	14240	—	pF	
C_{oss}	Output Capacitance	—	2130	—	pF	
C_{rss}	Reverse Transfer Capacitance	—	1460	—	pF	
C_{oss} eff. (ER)	Effective Output Capacitance (Energy Related)	—	2605	—	pF	$V_{GS} = 0\text{V}, V_{DS} = 0\text{V to } 32\text{V}$ ⑦
C_{oss} eff. (TR)	Effective Output Capacitance (Time Related)	—	2920	—	pF	

Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	426①	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ②	—	—	1524	A	
V_{SD}	Diode Forward Voltage	—	0.86	1.2	V	$T_J = 25^\circ\text{C}, I_S = 100\text{A}, V_{GS} = 0\text{V}$ ⑤
dv/dt	Peak Diode Recovery ④	—	2.7	—	V/ns	$T_J = 175^\circ\text{C}, I_S = 100\text{A}, V_{DS} = 40\text{V}$
t_{rr}	Reverse Recovery Time	—	52	—	ns	$T_J = 25^\circ\text{C}$ $V_R = 34\text{V}$, $T_J = 125^\circ\text{C}$ $I_F = 100\text{A}$
Q_{rr}	Reverse Recovery Charge	—	97	—	nC	$T_J = 25^\circ\text{C}$ $di/dt = 100\text{A}/\mu\text{s}$ ⑤
I_{RRM}	Reverse Recovery Current	—	2.3	—	A	$T_J = 25^\circ\text{C}$







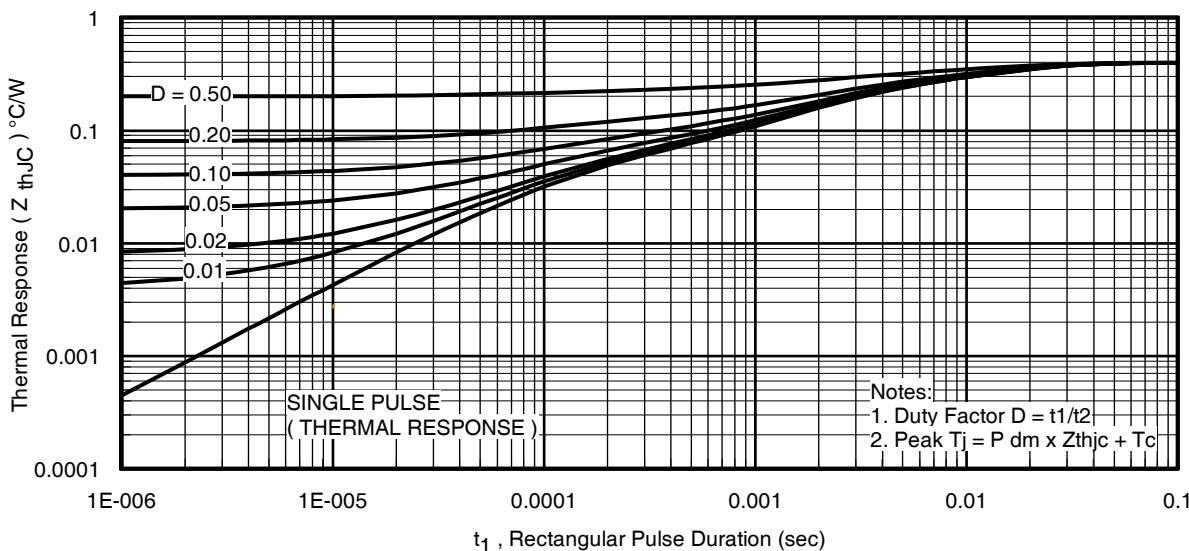


Fig 14. Maximum Effective Transient Thermal Impedance, Junction-to-Case

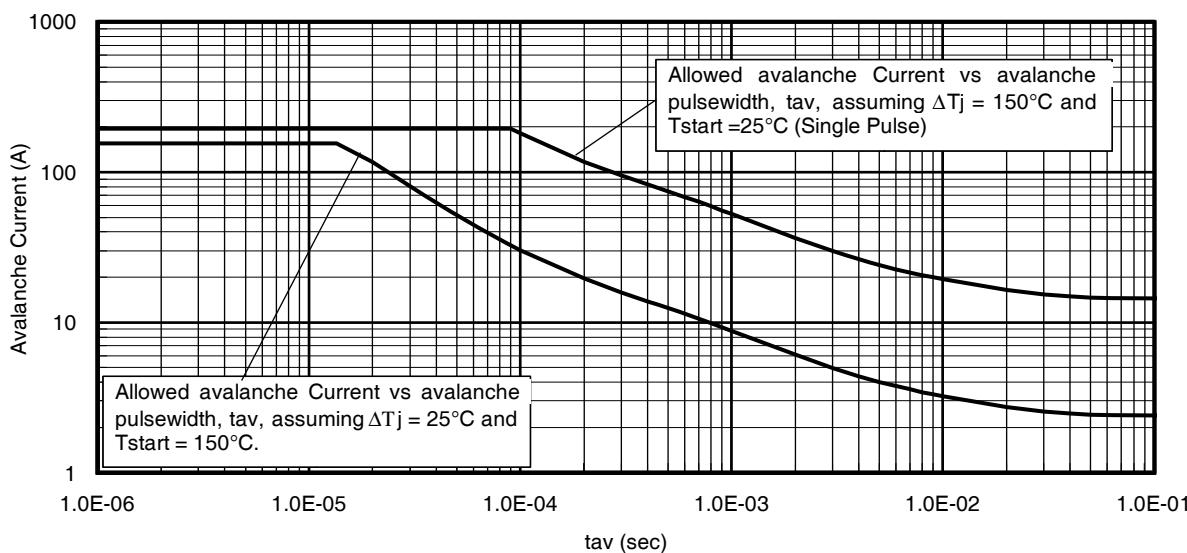


Fig 15. Avalanche Current vs.Pulsewidth

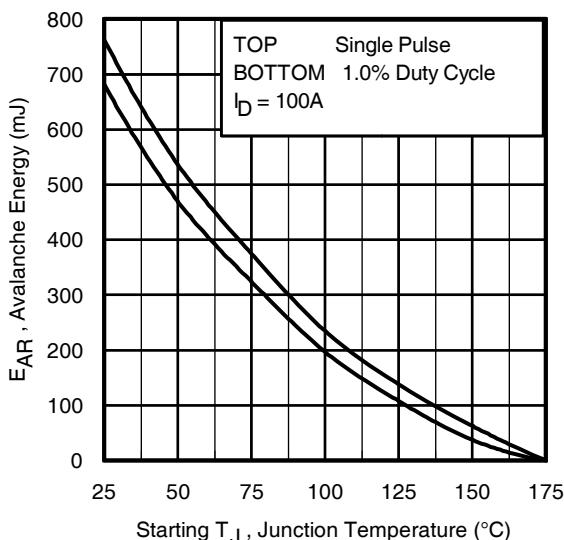


Fig 16. Maximum Avalanche Energy vs. Temperature

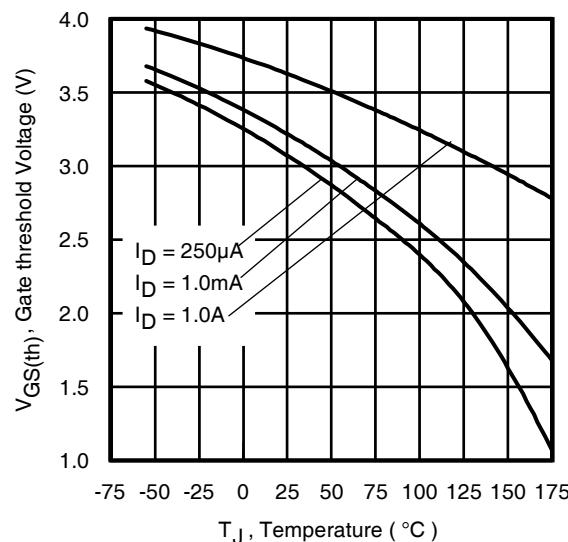
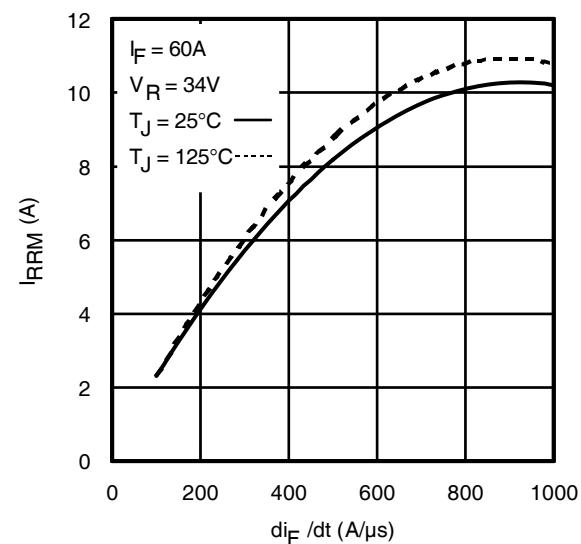
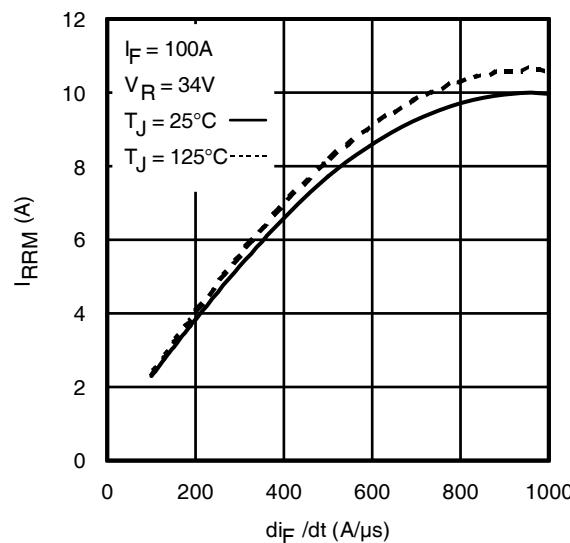
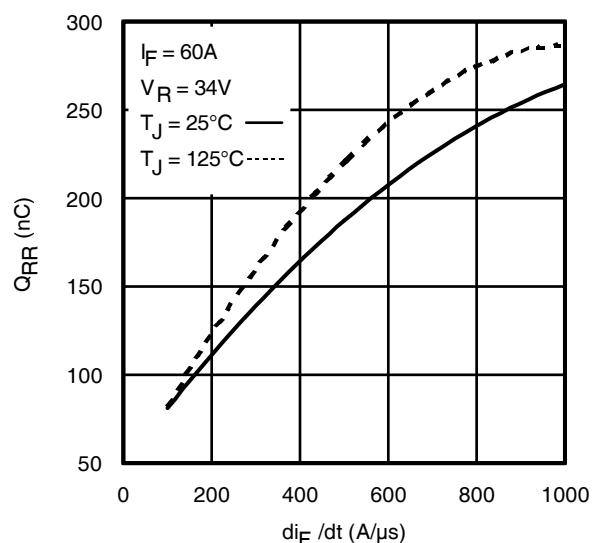
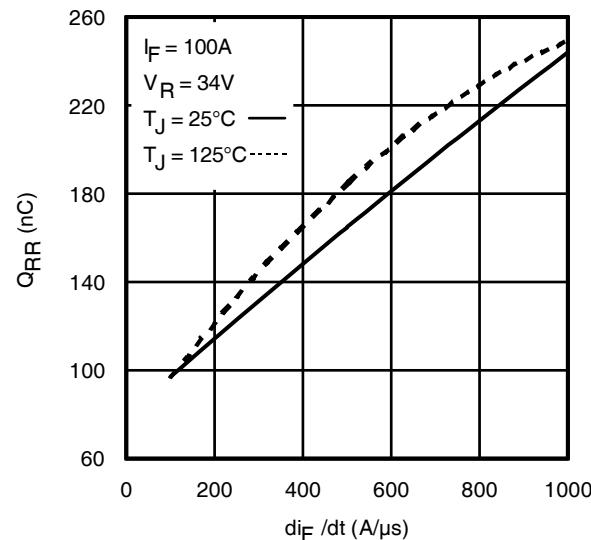
**Notes on Repetitive Avalanche Curves , Figures 15, 16:
(For further info, see AN-1005 at www.irf.com)**

1. Avalanche failures assumption:
Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 16a, 16b.
4. $P_D(\text{ave})$ = Average power dissipation per single avalanche pulse.
5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6. I_{av} = Allowable avalanche current.
7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).
- t_{av} = Average time in avalanche.
- D = Duty cycle in avalanche = t_{av} · f
- Z_{thJC}(D, t_{av}) = Transient thermal resistance, see Figures 14)

$$P_D(\text{ave}) = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$$

$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

$$E_{AS}(\text{AR}) = P_D(\text{ave}) \cdot t_{av}$$

**Fig. 17.** Threshold Voltage vs. Temperature**Fig. 18 -** Typical Recovery Current vs. di_F/dt **Fig. 19 -** Typical Recovery Current vs. di_F/dt **Fig. 20 -** Typical Stored Charge vs. di_F/dt **Fig. 21 -** Typical Stored Charge vs. di_F/dt

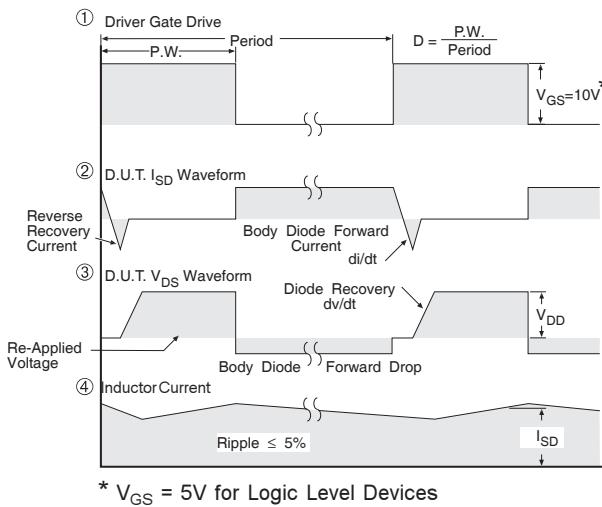
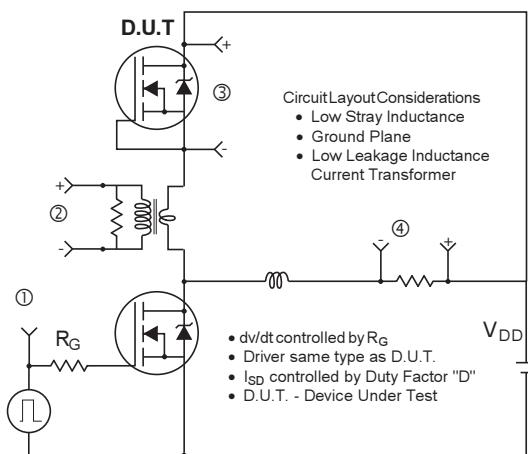


Fig 22. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

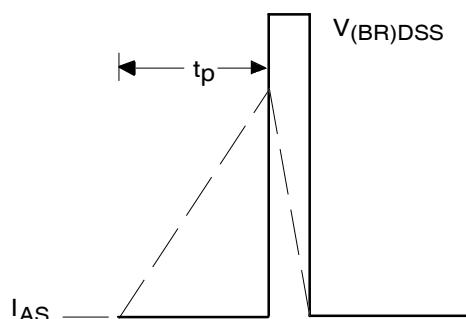
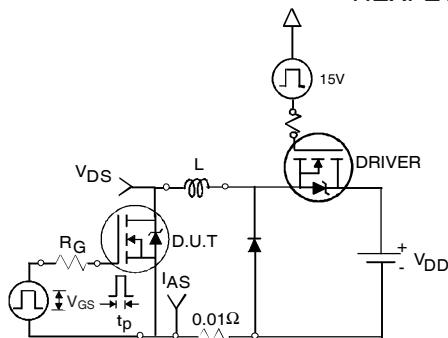


Fig 22a. Unclamped Inductive Test Circuit

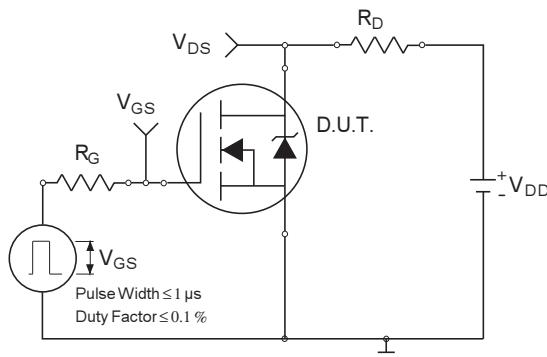


Fig 22b. Unclamped Inductive Waveforms

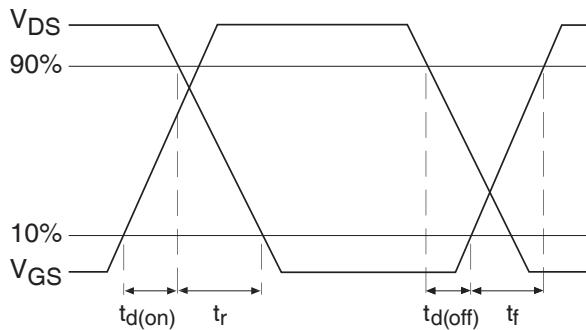


Fig 23a. Switching Time Test Circuit

Fig 23b. Switching Time Waveforms

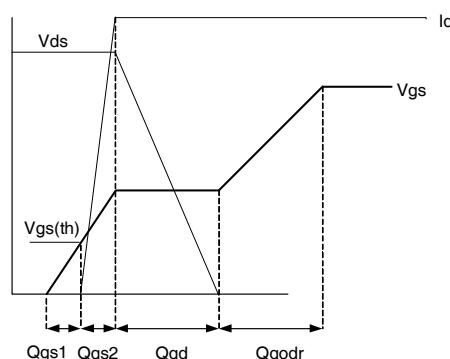
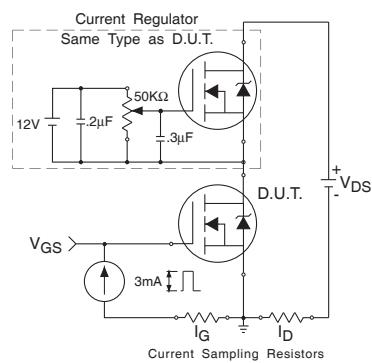
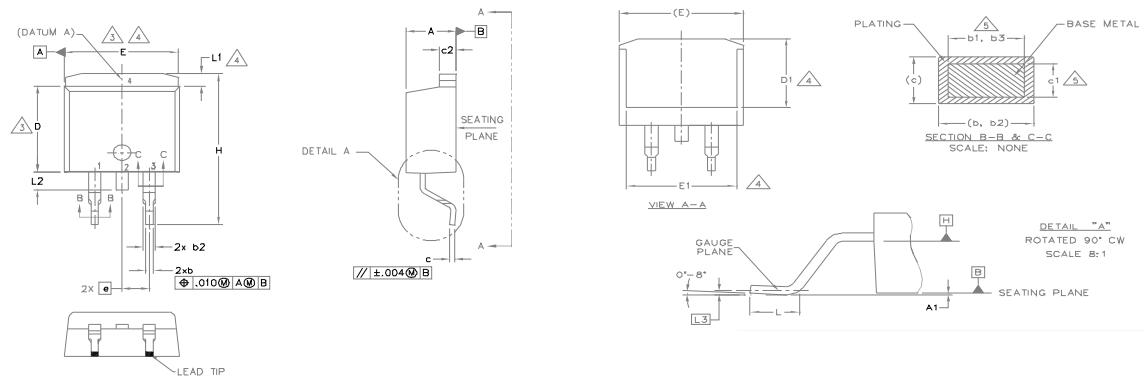


Fig 24a. Gate Charge Test Circuit

Fig 24b. Gate Charge Waveform

D²Pak (TO-263AB) Package Outline

Dimensions are shown in millimeters (inches)



S Y M B O L	DIMENSIONS				N O T E S	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	4.06	4.83	.160	.190		
A1	0.00	0.254	.000	.010		
b	0.51	0.99	.020	.039		
b1	0.51	0.89	.020	.035	5	
b2	1.14	1.78	.045	.070		
b3	1.14	1.73	.045	.068	5	
c	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023	5	
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	—	.270	—	4	
E	9.65	10.67	.380	.420	3,4	
E1	6.22	—	.245	—	4	
e	2.54 BSC		.100 BSC			
H	14.61	15.88	.575	.625		
L	1.78	2.79	.070	.110		
L1	—	1.68	—	.066		
L2	—	1.78	—	.070		
L3	0.25 BSC		.010 BSC			

NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
5. DIMENSION b1, b3 AND c1 APPLY TO BASE METAL ONLY.
6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
7. CONTROLLING DIMENSION: INCH.
8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

LEAD ASSIGNMENTS

DIODES

- 1.— ANODE (TWO DIE) / OPEN (ONE DIE)
- 2, 4.— CATHODE
- 3.— ANODE

HEXFET

- 1.— GATE
- 2, 4.— DRAIN
- 3.— SOURCE

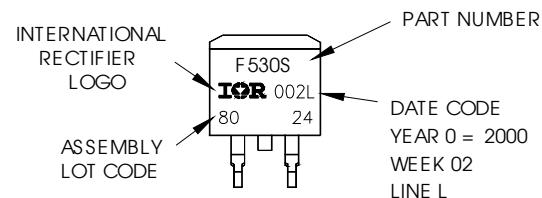
IGBTs, CoPACK

- 1.— GATE
- 2, 4.— COLLECTOR
- 3.— Emitter

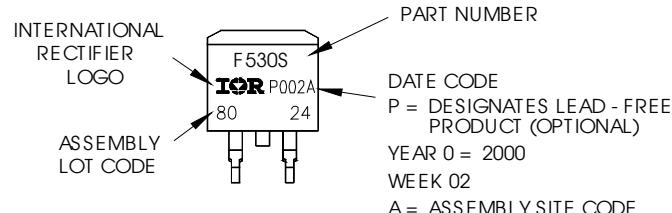
D²Pak (TO-263AB) Part Marking Information

EXAMPLE: THIS IS AN IRF 530S WITH
LOT CODE 8024
ASSEMBLED ON WW 02, 2000
IN THE ASSEMBLY LINE "L"

Note: "P" in assembly line position
indicates "Lead - Free"



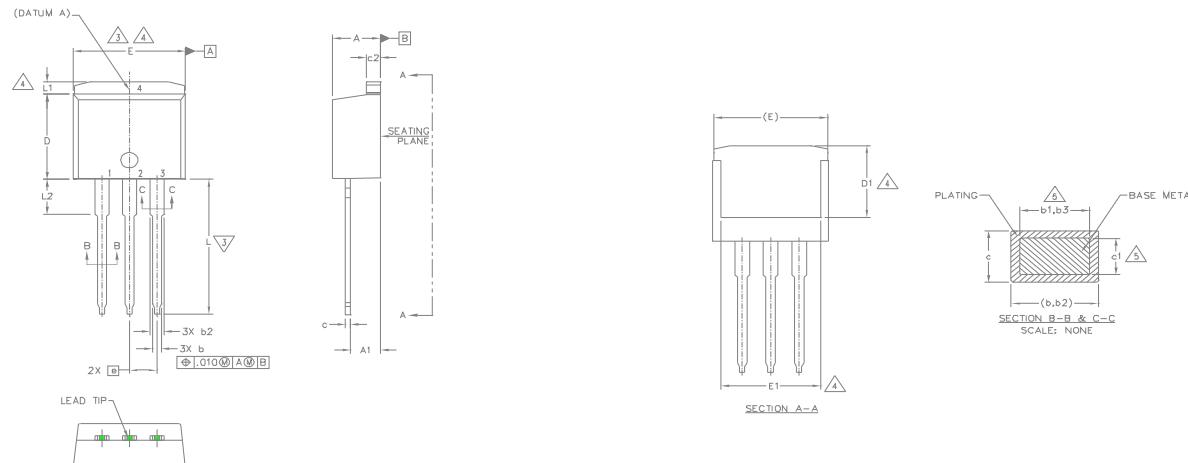
OR



Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

TO-262 Package Outline

Dimensions are shown in millimeters (inches)



SYMBOL	DIMENSIONS				NOTES	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	4.06	4.83	.160	.190		
A1	2.03	3.02	.080	.119		
b	0.51	0.99	.020	.039		
b1	0.51	0.89	.020	.035	5	
b2	1.14	1.78	.045	.070		
b3	1.14	1.73	.045	.068	5	
c	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023	5	
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	—	.270	—	4	
E	9.65	10.67	.380	.420	3,4	
E1	6.22	—	.245	—	4	
e	2.54	BSC	.100	BSC		
L	13.46	14.10	.530	.555		
L1	—	1.65	—	.065		
L2	3.56	3.71	.140	.146		

NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
5. DIMENSION b1 AND c1 APPLY TO BASE METAL ONLY.
6. CONTROLLING DIMENSION: INCH.
7. OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

LEAD ASSIGNMENTS

IGBTs, CoPACK

- 1.- GATE
- 2.- COLLECTOR
- 3.- Emitter
- 4.- COLLECTOR

HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN

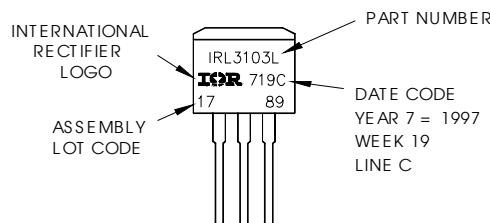
DIODES

- 1.- ANODE (TWO DIE) / OPEN (ONE DIE)
- 2, 4.- CATHODE
- 3.- ANODE

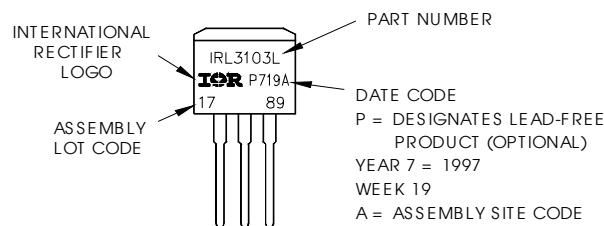
TO-262 Part Marking Information

EXAMPLE: THIS IS AN IRL3103L
LOT CODE 1789
ASSEMBLED ON WW 19, 1997
IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead - Free"

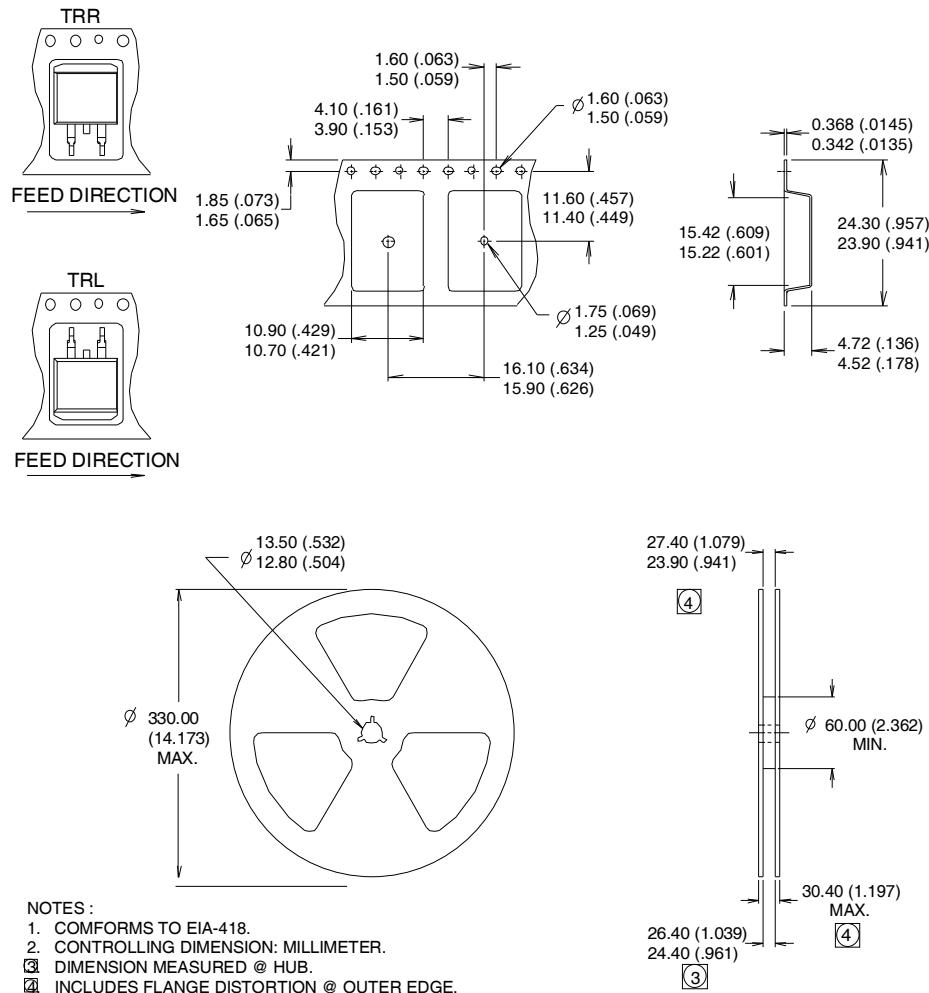


OR



Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

D²Pak (TO-263AB) Tape & Reel Information Dimensions are shown in millimeters (inches)



Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

Qualification information†

Qualification level	Industrial (per JEDEC JESD47F ^{††} guidelines)	
Moisture Sensitivity Level	D2Pak	MSL1 (per JEDEC J-STD-020D ^{††})
	TO-262	Not applicable
RoHS compliant	Yes	

† Qualification standards can be found at International Rectifier's web site: <http://www.irf.com/product-info/reliability/>

†† Applicable version of JEDEC standard at the time of product release.

Revision History

Date	Comment
11/6/2014	<ul style="list-style-type: none"> Updated $E_{AS}(L=1mH) = 1452mJ$ on page 2 Updated note 9 "Limited by T_{Jmax}, starting $T_J = 25^\circ C$, $L = 1mH$, $R_G = 50\Omega$, $I_{AS} = 54A$, $V_{GS} = 10V$". on page 2 Updated package outline on page 9 & 10

International
Rectifier

IR WORLD HEADQUARTERS: 101 N. Sepulveda Blvd., El Segundo, California 90245, USA
To contact International Rectifier, please visit <http://www.irf.com/whoto-call/>

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